Notice of References Cited

Application/Control No. 10/573,264	Reexamination	Applicant(s)/Patent Under Reexamination PELED ET AL.		
Examiner	Art Unit			
Son T. Nauven	3643	Page 1 of 1		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-3,812,619 A	05-1974	Wood et al.	47/58.1R
*	В	US-4,603,077 A	07-1986	Fujimoto et al.	442/62
*	С	US-5,428,123 A	06-1995	Ward et al.	528/28
*	D	US-6,156,842 A	12-2000	Hoenig et al.	525/171
*	E	US-2001/0004710 A1	06-2001	FELT et al.	623/17.12
*	F	US-2002/0083641 A1	07-2002	Leppard et al.	47/29.4
*	G	US-2004/0002729 A1	01-2004	Zamore, Alan M.	606/194
	Ι	US-			
		US-			
	7	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	DE19912996A1	09-2000	GERMANY	KLEEMISS ET AL.	A01G 9/14
	0	JP2003009680A	01-2003	JAPAN	HASHIMOTO ET AL.	A01G 13/00
	Р	JP2003105183A	04-2003	JAPAN	MIYAHARA	A01G 9/14
	Q	WO00/63282	10-2000	WIPO	SATANI ET AL.	C08K 5/00
	R					
	S					
	Т				·	

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
U					
V					
w					
X					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.